

10/12/25



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Errors-on-errors in xFitter

Enzo Canonero

Glen Cowan

Motivation



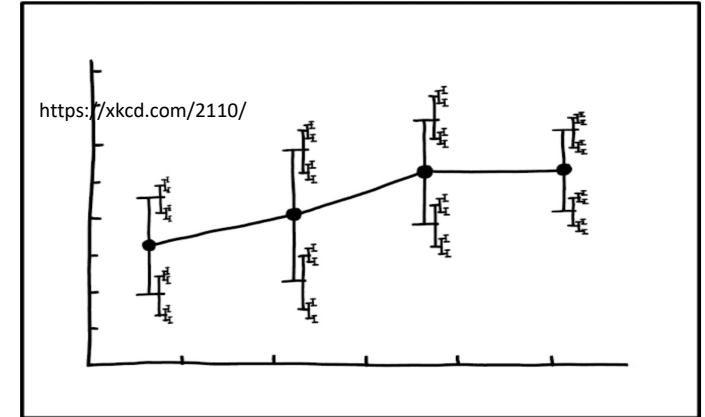
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1) *Some systematic uncertainties* can be well estimated:

- Related to stat. error of control measurements
- Related to size of MC event sample

2) But they can also be *quite uncertain*:

- Theory systematics
- Two points systematics



References:

Full model: [Eur. Phys. J. C 85.2 \(2025\)](https://doi.org/10.1140/epjc/s10050-025-11002-1)

My thesis: [RHUL pure](https://pure.rhul.ac.uk/record/1000000000000000000)

Standalone toolkit: [GitHub](https://github.com/robertmroberts/TwoPoints)

Higher order asymptotics studies: [Eur. Phys. J. C \(2023\) 83:1100](https://doi.org/10.1140/epjc/s10050-023-11000-8)

Motivation

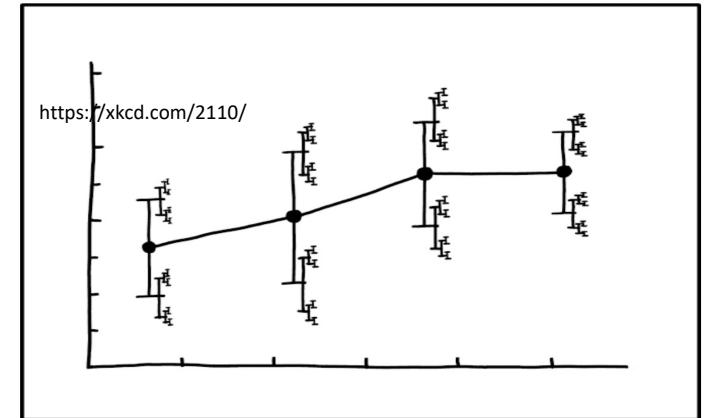


1) *Some systematic uncertainties* can be well estimated:

- Related to stat. error of control measurements
- Related to size of MC event sample

2) But they can also be *quite uncertain*:

- Theory systematics
- Two points systematics
- Non-trivial consequences:
 - Fits are pulled less by incompatible data
 - Incompatible data are treated as an extra source of uncertainty resulting in inflated confidence intervals



References:

Full model: [Eur. Phys. J. C 85.2 \(2025\)](https://doi.org/10.1140/epjc/s10050-025-10600-1)

My thesis: [RHUL pure](https://pure.rhul.ac.uk/record/1000000000000000000)

Standalone toolkit: [GitHub](https://github.com/robertmoran/standalone_toolkit)

Higher order asymptotics studies: [Eur. Phys. J. C \(2023\) 83:1100](https://doi.org/10.1140/epjc/s10050-023-1100)

Formulation of the problem



- Suppose measurements \mathbf{y} have a probability density $P(\mathbf{y}|\boldsymbol{\mu}, \boldsymbol{\theta})$
 - $\boldsymbol{\mu}$ = Parameters of interest
 - $\boldsymbol{\theta}$ = Nuisance parameters
- Auxiliary Measurements \mathbf{u} are used to provide info on nuisance parameters and are (often) assumed to be independently Gaussian distributed
- The resulting Likelihood is:

$$L(\boldsymbol{\mu}, \boldsymbol{\theta}) = P(\mathbf{y}, \mathbf{u}|\boldsymbol{\mu}, \boldsymbol{\theta}) = P(\mathbf{y}|\boldsymbol{\mu}, \boldsymbol{\theta}) \times \prod_i \frac{1}{\sqrt{2\pi}\sigma_{u_i}} e^{-(\mathbf{u}_i - \theta_i)^2/2\sigma_{u_i}^2}$$

*Can be a real measurement
or just our best guess based
on theoretical reasons*

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- And the log Likelihood:

$$\log L(\boldsymbol{\mu}, \boldsymbol{\theta}) = \log P(\mathbf{y}|\boldsymbol{\mu}, \boldsymbol{\theta}) - \sum \frac{(\mathbf{u}_i - \boldsymbol{\theta}_i)^2}{2\sigma_{u_i}^2}$$

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Let systematic errors be
potentially uncertain!

Gamma Variance Model (GVM)



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- The original **quadratic terms** in the log likelihood replaced by **logarithmic terms**:

$$\sum_i \frac{(u_i - \theta_i)^2}{2\sigma_{u_i}^2} \longrightarrow \sum_i \left(1 + \frac{1}{2\epsilon_i^2}\right) \log \left(1 + 2\epsilon_i^2 \frac{(u_i - \theta_i)^2}{\sigma_{u_i}^2}\right)$$

ϵ = error-on-error parameter

$\epsilon = 0.3$ means 30%
uncertainty on σ

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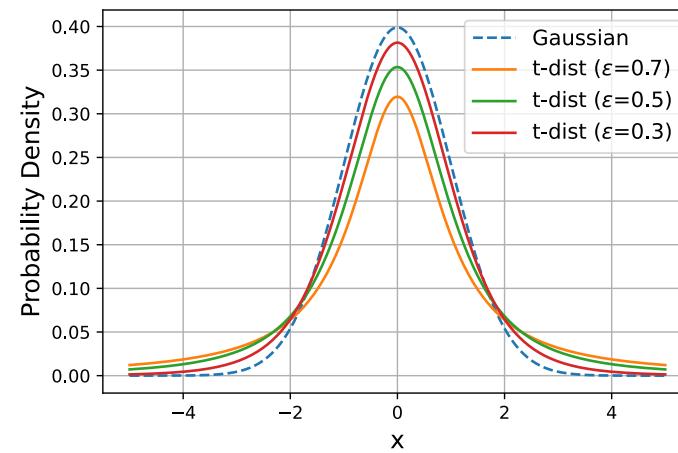
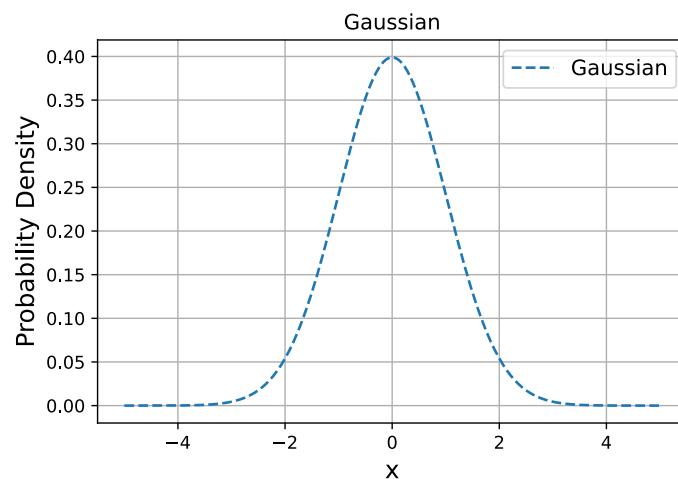


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ϵ = error-on-error parameter

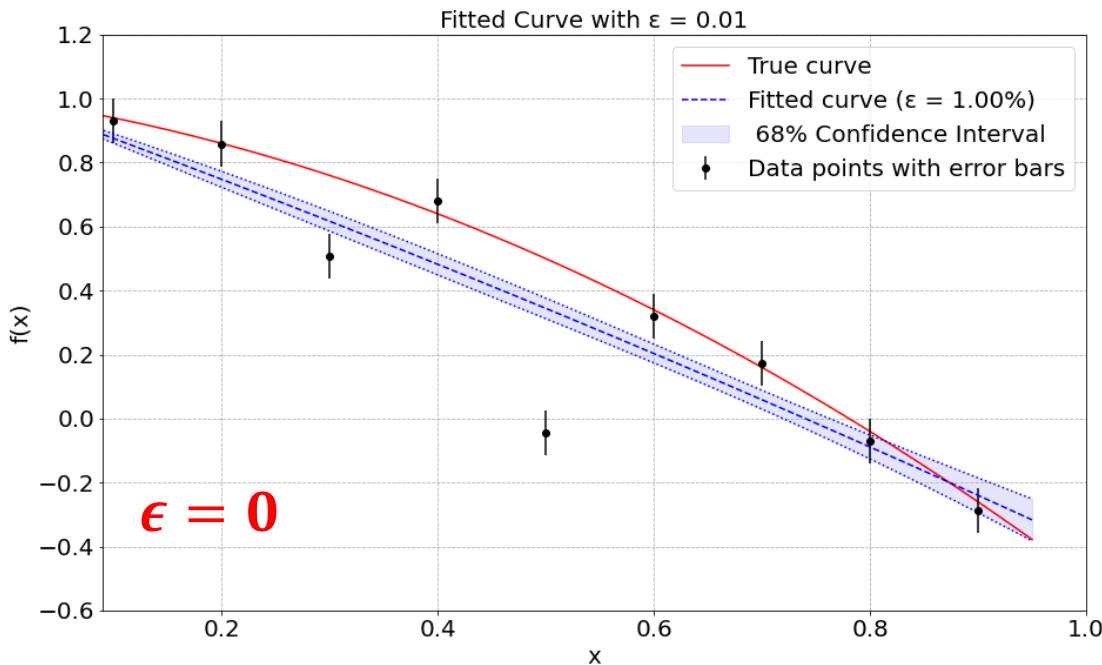
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- Equivalent to switch from **Gaussian constraints** to **Student's t constraints** for systematics:



Fitting of a curve: compatible measurements

- Fit of a quadratic function with two outliers



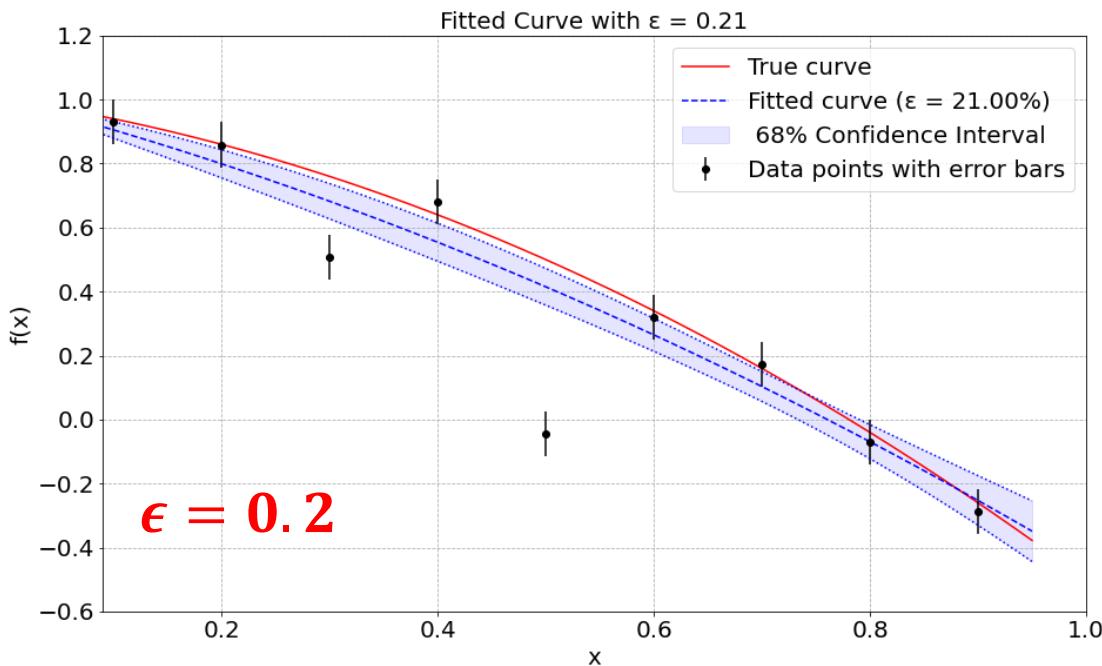
$$y_i \sim f(x_i) + \theta_i$$

Params of interest

$$f(x_i) = ax_i^2 + bx + c$$

Fitting of a curve: compatible measurements

- Fit of a quadratic function with two outliers



$$y_i \sim f(x_i) + \theta_i$$

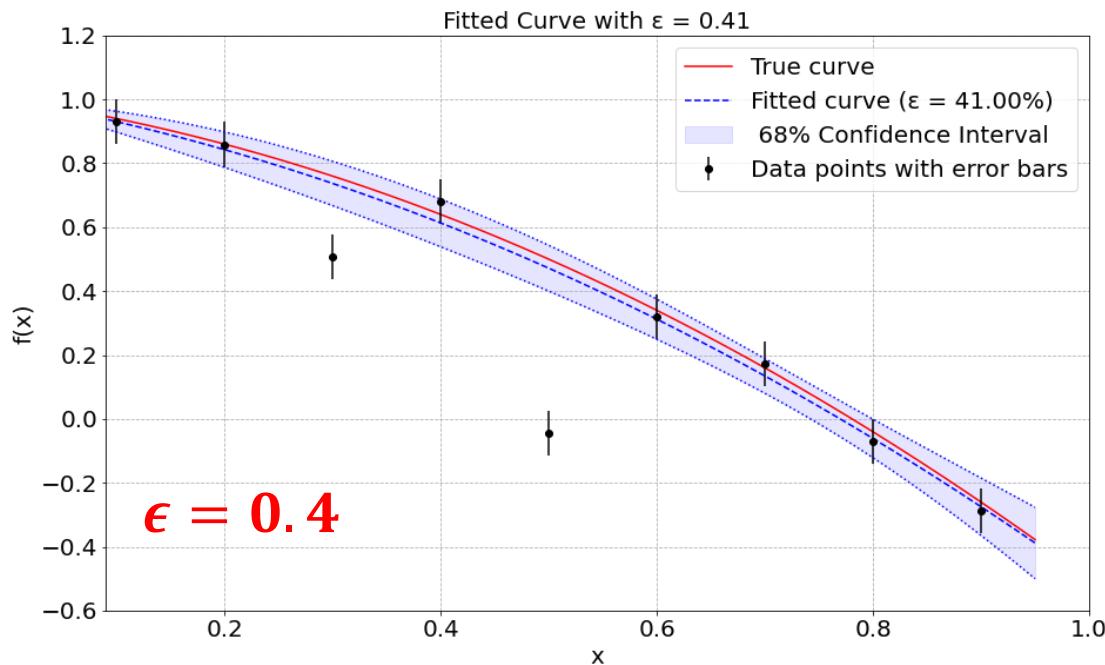
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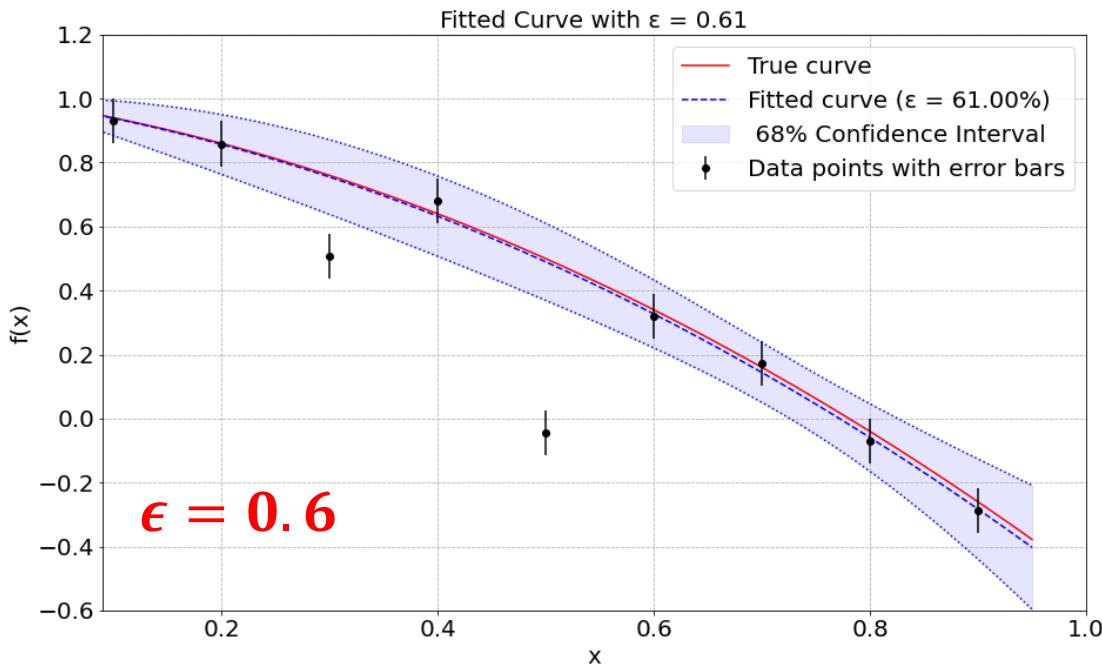
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Fitting of a curve: compatible measurements

- Fit of a quadratic function with two outliers



$$y_i \sim f(x_i) + \theta_i$$

Params of interest

$$f(x_i) = ax_i^2 + bx + c$$

- Gamma Variance Model:

$$\chi^2 = \sum_i \frac{(y_i - f_i(\boldsymbol{a}) - \sum_s \Gamma_i^s \theta_s)^2}{\sigma_i^2} + \sum_s \left(1 + \frac{1}{2\boldsymbol{\varepsilon}_i^2} \right) \log(1 + 2\boldsymbol{\varepsilon}_i^2 \theta_i^2)$$

- Applicable both to additive and multiplicative systematics as only the systematic terms in the chi2 are being changed

$$\chi^2 = \sum_i \frac{(y_i - f(\boldsymbol{a}) - \sum_s \Gamma_i^s \theta_s)^2}{\sigma_i^2} + \sum_s \left(1 + \frac{1}{2\boldsymbol{\varepsilon}_i^2} \right) \log(1 + 2\boldsymbol{\varepsilon}_i^2 \theta_i^2)$$

- How do I minimize with respect to θ ?
 - Numerically -> Treat θ as external
 - Analytically -> Expand the log in $\boldsymbol{\varepsilon}$
- In general just a subsample of systematics need a numerical minimization (only those with Large pulls)
- All the others can be minimized with the analytical approach

- Correction factors needed to account for the non-Gaussianity of the χ^2 (log-terms)
 - Goodness-of-fit: $\chi^2 \rightarrow \frac{\chi^2}{b_{\chi^2}}$
 - Covariance matrix $V \rightarrow V * b_V$
- In general $b_{\chi^2} \neq b_V$
- Non-negligible if number EonE $> \sim 10$



- **Steering.txt**

- Specify whether to treat each systematic uncertainty as **External** or **Nuisance** (already implemented).
- Specify the **error-on-error** value.
- Specify the number of **iterations** for the analytical procedure.
- Specify whether to enable **Bartlett corrections**.

```
&Systematics
  ListOfSources = 'sysHZComb1053:E', 'proc_tb21:E'

  Epsilon = 0.61, 0.61
  n_iterations = 4
  Enable_Bartlett = .true.

&End
```



- Systematics.inc
 - Initialize errors-on-errors related variables

```
C Errors-on-Errors settings
logical      EoEEEnabled
integer      EoE_n_iterations
logical      EoEActive(NSYSMAX)
double precision EoEEpsilon(NSYSMAX)

common/CEonE/ EoEEEnabled, EoE_n_iterations, EoEActive, EoEEpsilon

C --- Bartlett corrections for EoE
logical BartlettEnabled
double precision BartlettLRFactor
double precision BartlettGoFFactor
double precision BartlettSysFactor(NSysMax)
common/CBartlett/ BartlettEnabled, BartlettLRFactor, BartlettGoFFactor, BartlettSysFactor
```

- Read_steer.f

1. Set defaults (Set_Defaults)
2. Read steering file (read_systematics)

```
C E-on-E defaults
  EoEEEnabled      = .false.
  EoE_n_iterations = 2
  do i=1,NSYSMAX
    EoEActive(i)  = .false.
    EoEEpsilon(i) = 0.0D0
  enddo

C Bartlett defaults
  BartlettEnabled      = .true.
  BartlettLRFactor    = 0.0D0
  BartlettGoFFactor   = 0.0D0
  do i=1,NSYSMAX
    BartlettSysFactor(i) = 0.0D0
  enddo
```



```
C --- Inspect Epsilon() from &Systematics
neps = 0
do i=1,nsys
    if (Epsilon(i) .gt. -1.0D98) then
        if (Epsilon(i) .lt. 0.0D0) then
            call hf_errlog(29092502,'F: Epsilon(i) must be >= 0 or unset')
            call hf_stop
        endif
        neps = neps + 1
    endif
enddo

C Only proceed if there is at least one non-negative value
if (neps .gt. 0) then
    if (neps .eq. nsys) then
        do i=1,nsys
            if (Epsilon(i) .gt. 0.0D0) then
                EoEEpsilon(i) = Epsilon(i)
                EoEActive(i) = .true.
            else
                EoEEpsilon(i) = 0.0D0
                EoEActive(i) = .false.
            endif
        enddo
    else
        call hf_errlog(29092501,
$ 'F: Systematics/Epsilon must be length(NSources)')
        call hf_stop
    endif
endif
```

Code is thoroughly commented

- getchisquare.f

chi2_calc_chi2: Set log-constrain if EonE are active for systematic K

```
C Correlated chi2 part:
  fcorchi2_in = 0.d0
  do k=1, NSys
    if (SysForm(k) .eq. isNuisance .or. SysForm(k) .eq. isExternal) then
      if (EoEEEnabled .and. EoEActive(k)) then
        temp_val = 2.0D0 * EoEEpsilon(k)**2 * rsys_in(k)**2 * SysPriorScale(k)
        fcorchi2_in = fcorchi2_in
        $      + (1.0D0 + 1.0D0/(2.0D0*EoEEpsilon(k)**2))
        $      * log(1.0D0 + temp_val)
      else
        fcorchi2_in = fcorchi2_in + rsys_in(k)**2 * SysPriorScale(k)
      endif
    endif
```



chi2_calc_syst_shifts: Iterate to minimize analytically sources with active EoE

```
C EoE (errors-on-errors) iterations for nuisance sources
    if (EoEEEnabled) then
        do iter = 1, EoE_n_iterations

C reset incremental shifts
    do i=1,nsys
        shift1(i) = 0.0D0
    enddo

C rebuild A and C; diagonal = prior
    do i=1,nsys
        C(i) = 0.0D0
        do j=1, nsys
            A(i,j) = 0.0D0
        enddo

C quadratic prior by default; switch to EoE log prior if active (nuisance only)
    if ( SysForm(i) .eq. isNuisance ) then
        if (EoEActive(i)) then
            Numerator_eps  = 1.0D0 + 2.0D0 * EoEEpsilon(i)**2
            Denominator_eps = ( 1.0D0 / SysPriorScale(i) )
                                + 2.0D0 * EoEEpsilon(i)**2 * shift0(i)**2
$
```



chi2_calc_syst_shifts: Compute Bartlett factors, if **EnableBartlett** is set to **True**

```
C Account for Bartlett factors
  if (iflag.eq.3) then
    if (BartlettEnabled .and. EoEEEnabled) then
      do i = 1, nsys
        if (SysForm(i) .eq. isNuisance) then
          BartlettSysFactor(i) = 0.0D0
          if (EoEActive(i)) then
            eps2 = EoEEpsilon(i)*EoEEpsilon(i)
            j_ii = A(i,i)
            sigma_u2 = ( 1.0D0 / SysPriorScale(i) ) + ( 2.0D0*eps2*shift0(i)*shift0(i) ) / ( 1.0D0 + 2.0D0*eps2 )

            ratio = j_ii / sigma_u2

            b_theta = ( 4.0D0*ratio - ratio*ratio ) * eps2
            BartlettSysFactor(i) = b_theta
          endif
        endif
      enddo
    endif
  endif

C Apply Bartlett factors to ersys_in
  do l=1,nsys
    if ( SysForm(l) .eq. isNuisance ) then
      rsys_in(l) = shift0(l)
      if (iflag.eq.3) then
        ersys_in(l) = sqrt(A(l,l)) * ( 1 + BartlettSysFactor(l) )
      endif
    endif
  enddo
```

- fcn.f

Process Bartlett factors

```
! ----- Bartlett-only-for-printing scaling -----
nExtSyst = 0
do i=1,nsys
  if ( SysForm(i) .eq. isExternal) then
    nExtSyst = nExtSyst + 1
  endif
enddo

nPOI = nparFCN - nExtSyst
print *, 'External sysys = ', nExtSyst
c_bart_chi2 = 1.0D0
c_bart_ci = 1.0D0
if (BartlettEnabled .and. EoEEEnabled) then
  if (ndf .gt. 0) then
    c_bart_chi2 = 1.0D0 / ( 1.0D0 + BartlettGoFFactor / dble(ndf) )
    c_bart_ci  = sqrt(1.0D0 + BartlettLRFactor / dble(nPOI))
    ! Warn only when Bartlett is active and reduces printed values
    if (c_bart_chi2 .lt. 1.0D0) then
      call hf_errlog(25100101,
$'W: c_bart_chi2 < 1; mathematically should be <=1, consider setting Enable_Bartlett = .false.')
      endif
    endif
  endif
endif
```



Apply Bartlett factors only when printing the results. The function's return value is left unchanged, so other methods that call it are not affected.

```
! Scale ONLY what we print:  
chi2out_print = chi2out * c_bart_chi2
```

- error_bands_pumplin.f

Error_Bands_Pumplin: Compute Bartlett factors to rescale confidence intervals

```
nExtSyst = 0
do i=1,nsys
  if ( SysForm(i) .eq. isExternal) then
    nExtSyst = nExtSyst + 1
  endif
enddo

nPOI = nparFCN - nExtSyst
c_BartLR  = 1.0D0
bart_scale = 1.0D0
if (BartlettEnabled .and. EoEEEnabled) then
  if (nPOI .gt. 0) then
    c_BartLR = 1.0D0 + BartlettLRFactor/dble(nPOI)
    bart_scale = sqrt(c_BartLR)
  endif
endif
```



Error_Bands_Pumplin: Apply these factors to the eigen-vector shifts

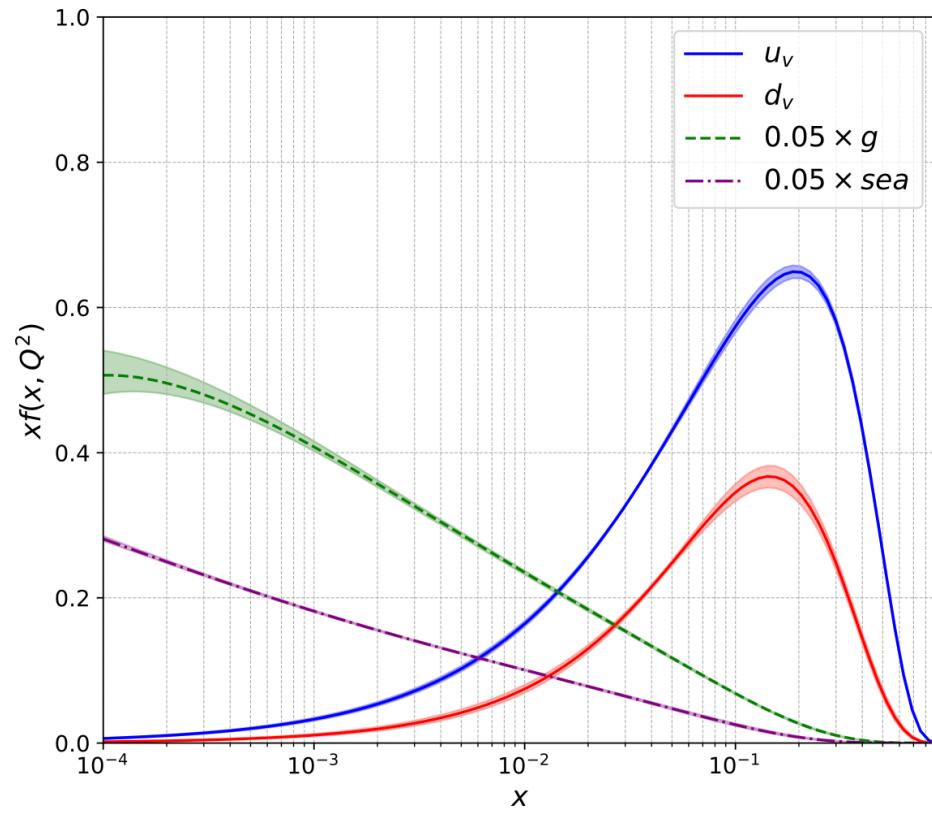
```
C
C Shift parameters by the j-th de-correlated error:
C
    do i=1,npar
        a(i) = pkeep(i)
        iint = iunint(i)
        if (iint.gt.0) then
            if(doOffset) then
                shift = shift_dir * DecorVarShift(iint, j)
            else
                call MNSTAT(fmin, fedm, errdef, npari, nparx, istat)    !> MW&FG for scaling with DeltaChi2>1.0
                shift = shift_dir * GetUmat(iint,j)*SQRT(errdef)      !> MW&FG for scaling with DeltaChi2>1.0
            endif
            shift = shift * bart_scale
            a(i) = a(i) + shift
        endif
    enddo  ! i
```

ErrBandsSym: same implementation

PDF fits determine the parton momentum distributions inside hadrons from a global set of experimental cross-section data.

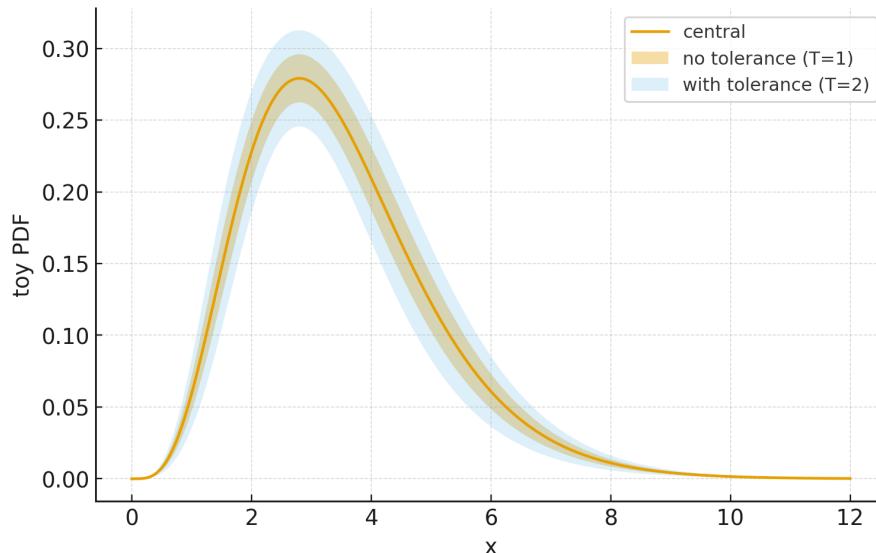
Mutual tension:

- PDFs from different experiments often disagree at the level of their quoted experimental uncertainties
- When combined they often yield values $\chi^2 / DOF > 1$
- Alm: assign “errors on errors” to the experimental uncertainties of the fit dataset



Problem: Often in PDF fits one finds values of $\frac{\chi^2}{Dof} > 1$ due to tensions among diverse datasets

Solution: In PDF fits a tolerance^[*] $T > 1$ replaces $\Delta\chi^2 = 1$ by $\Delta\chi^2 = T^2$ so that the quoted confidence intervals have correct coverage



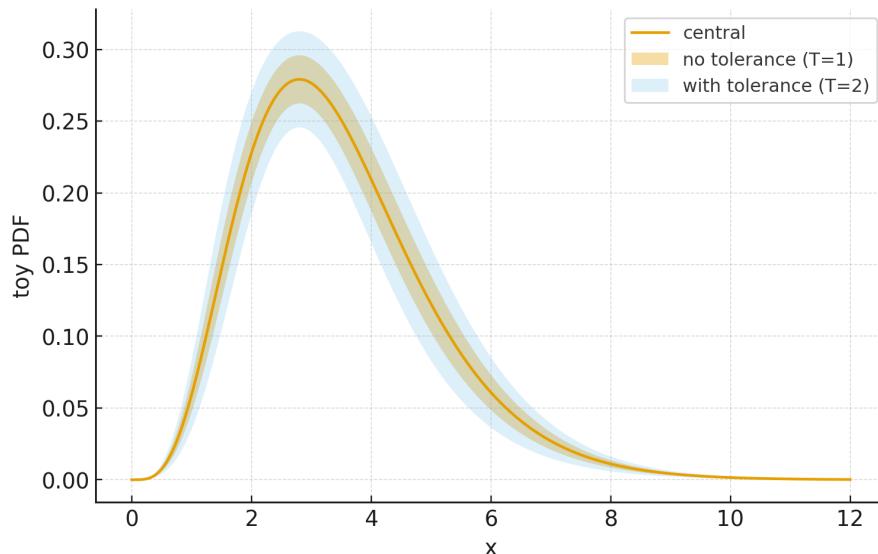
Why $T > 1$:

- Misestimated errors/correlations
- Parametrization/fit
- Theoretical predictions
- Non-Gaussian likelihoods

[*] [Eur. Phys. J. C 63 \(2009\)](https://doi.org/10.1140/epjc/s10050-009-0970-9)

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- ✓ Non-Gaussian likelihoods

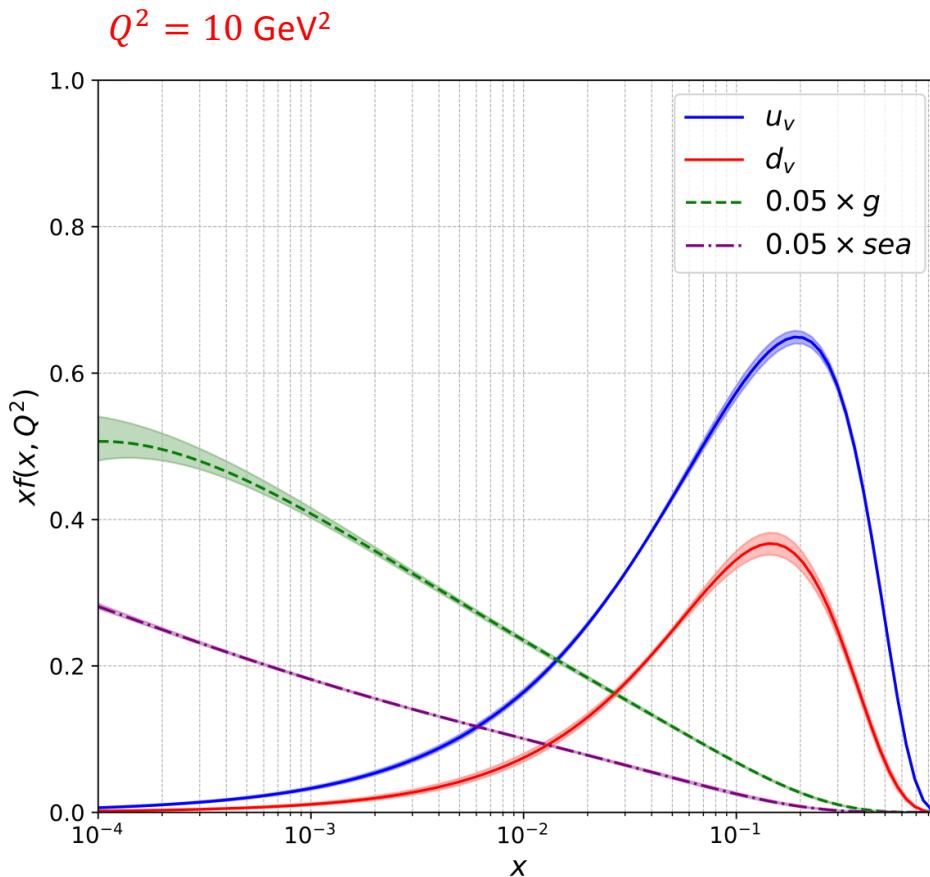
These two points are addressed by the errors-on-errors framework simultaneously

[*] [Eur. Phys. J. C 63 \(2009\)](https://doi.org/10.1140/epjc/s10050-009-0970-9)

HERA combined dataset



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- With $\epsilon = 0$, we reproduce the results of the Hera fit:

$$\frac{\chi^2}{DOF} = \frac{1363}{1131}$$

- We use the fit setup and parametrization of the combined HERA dataset paper^[*]

[*]: Eur. Phys. J. C 75.12 (2015)

- 169 systematic sources in the fit (Bartlett factor matters!)

- Group them in three categories^[*]

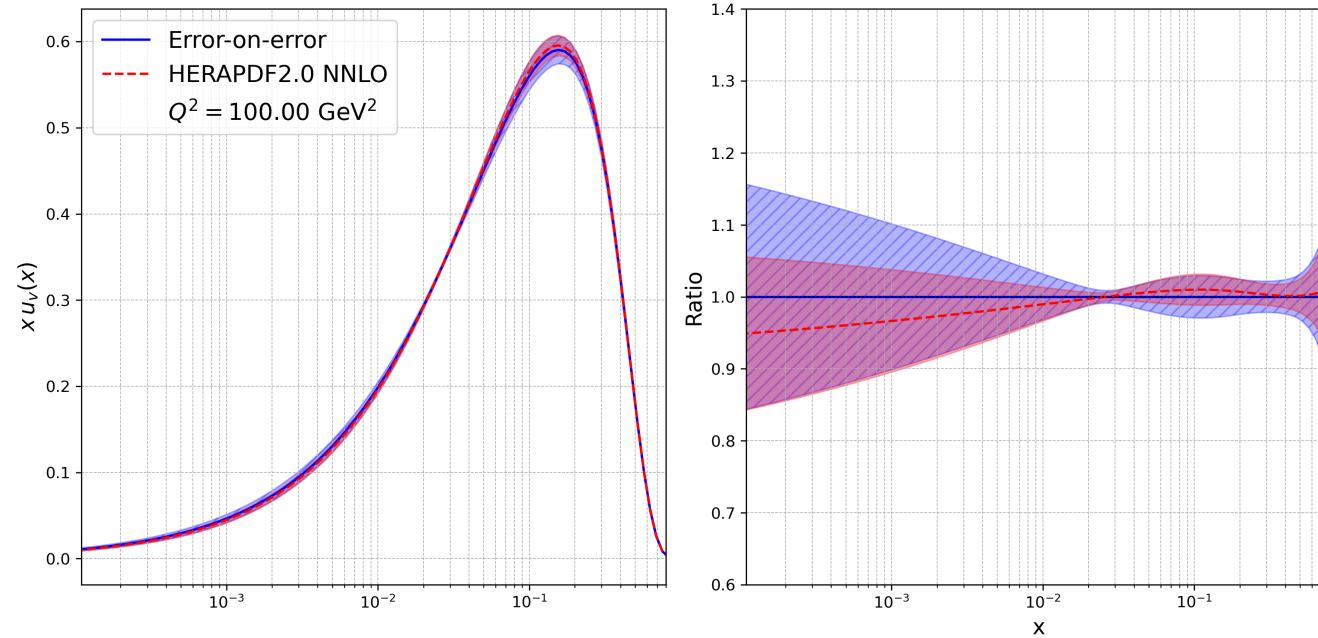
- "Ugly" systematics $\epsilon_s = 0.6$ (32)
- "Bad" systematics $\epsilon_s = 0.3$ (12)
- "Good" systematics $\epsilon_s = 0.0$ (125)

$$\frac{\chi^2}{DOF} = \frac{1363}{1131} \longrightarrow \frac{1315}{1131}$$

[*] backup

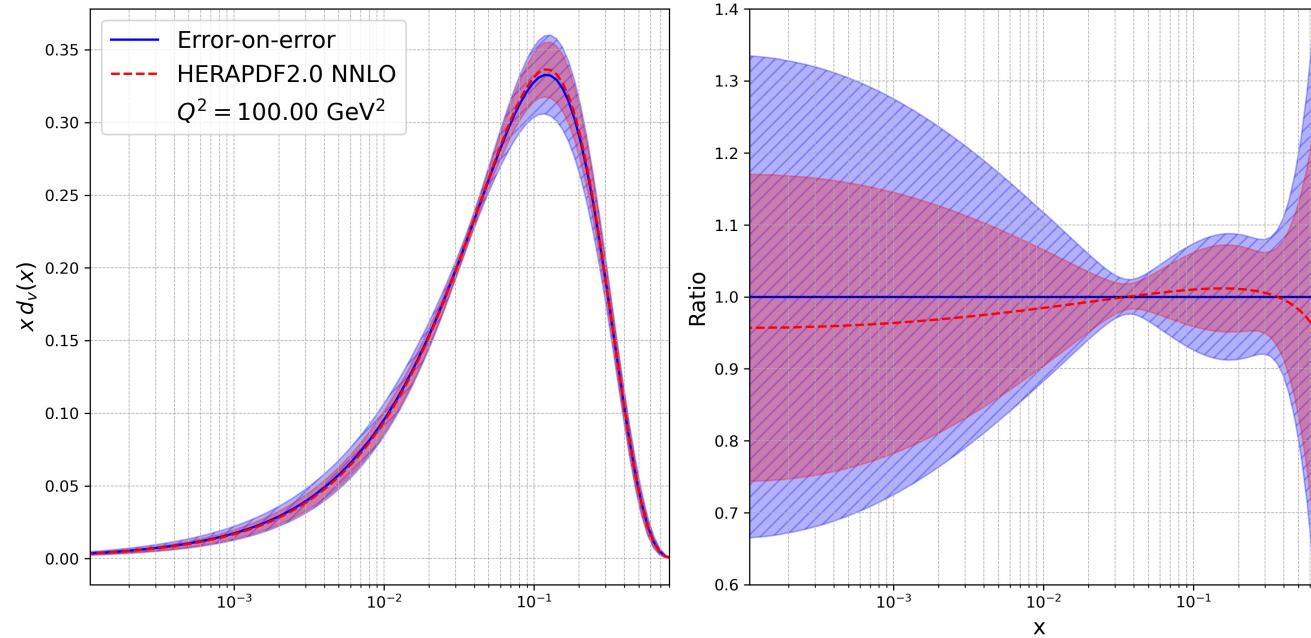
1. Valence up-quark PDF

$$Q^2 = 1.9 \text{ GeV}^2$$



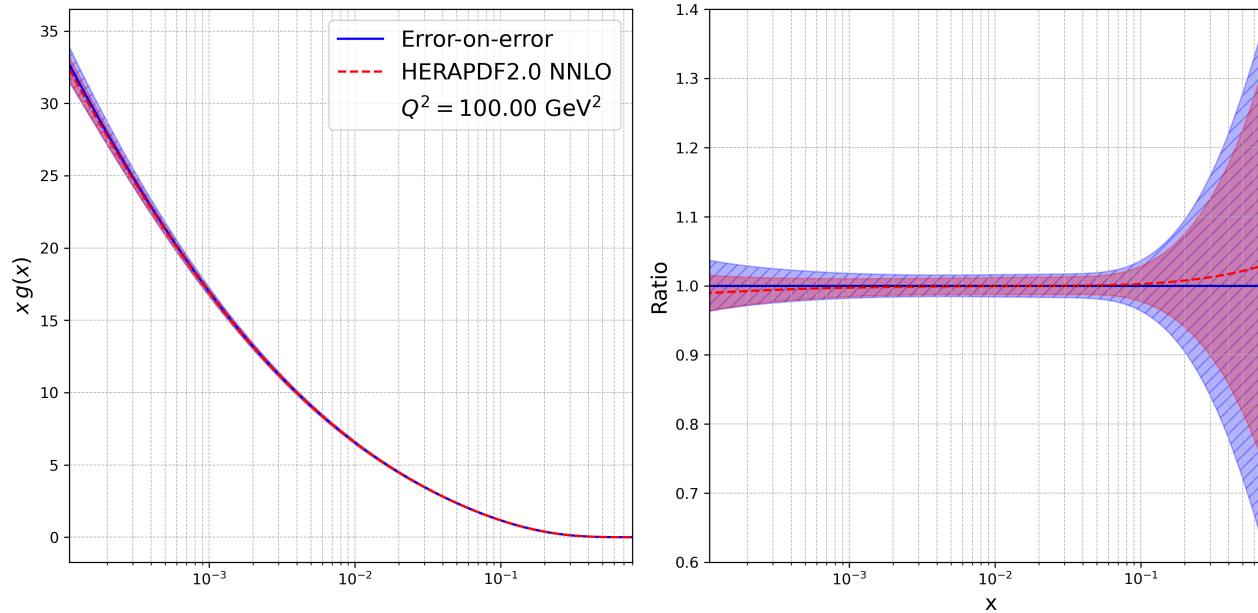
1. Valence down-quark PDF

$$Q^2 = 1.9 \text{ GeV}^2$$



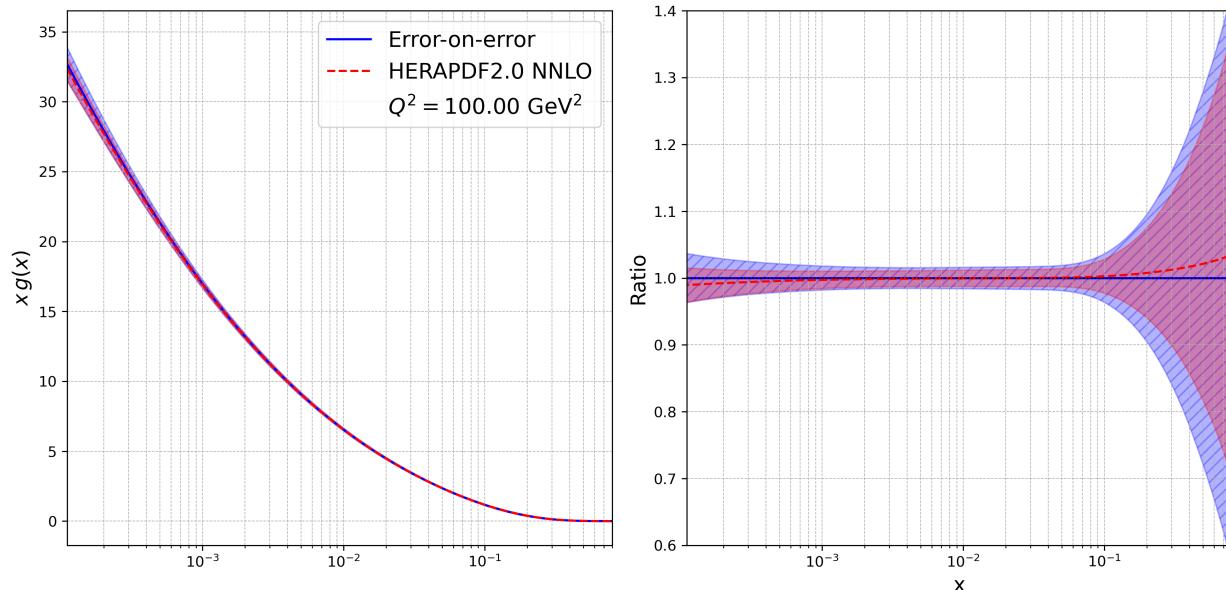
2. Gluon PDF

$$Q^2 = 1.9 \text{ GeV}^2$$



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$Q^2 = 1.9 \text{ GeV}^2$



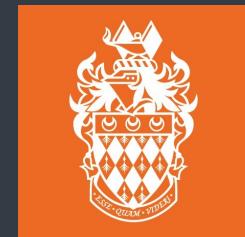
Comments:

- PDFs are modified in regions where the data are less well modelled or exhibit tensions
- Specifically, low Q^2 region ($3.5 < Q^2 < 10$) GeV^2



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Thank you for your attention

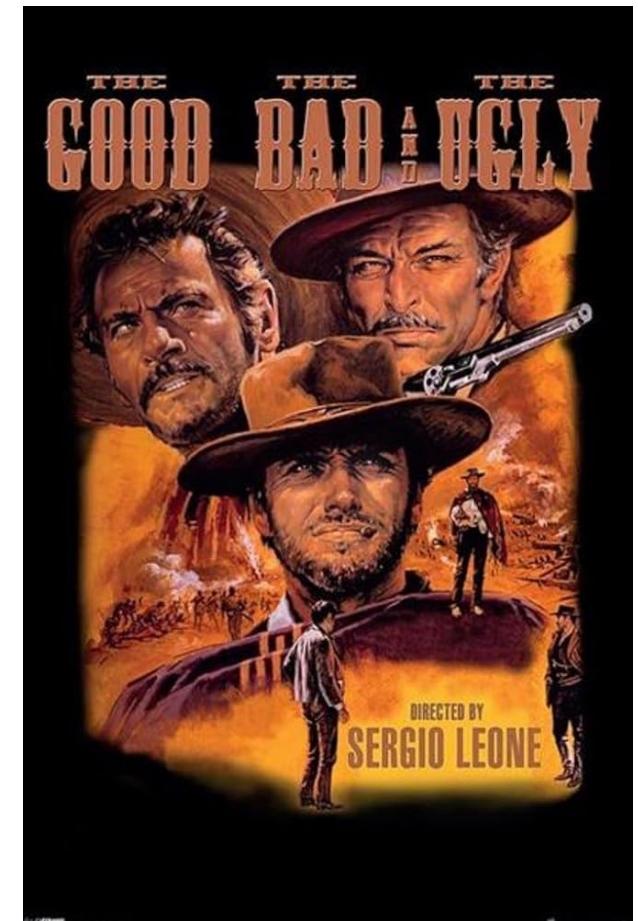


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Back-up slides

Particle physics experiments face a vast variety of systematic uncertainties*:

- **“Good” Systematics:**
 - Statistically driven uncertainties (your own calibrations)
 - Clear probabilistic model
- **“Bad” Systematics:**
 - Do not reliably improve with more data
 - E.g: external results, analysis methodology biases, ...
- **“Ugly” Systematics:**
 - Theory uncertainties
 - No well-defined sampling distribution
 - Treated via ad-hoc prescriptions

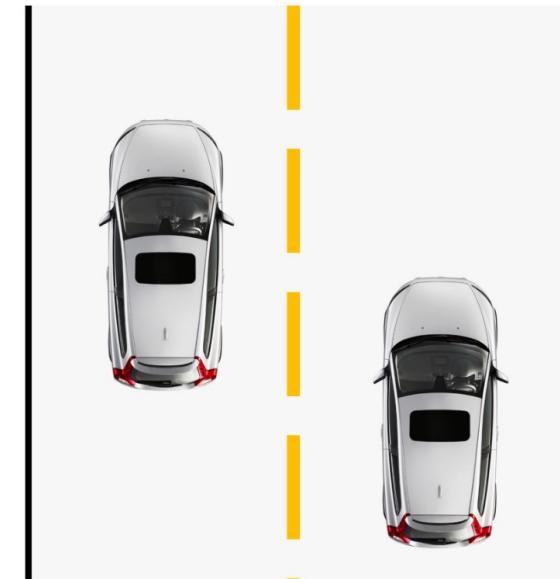


*Pekka Sinervo – PHYSTAT 2003, [Nicholas Wardle](#)

Compare two models \mathcal{O}_1 and \mathcal{O}_2 and define:

$$\hat{\mathcal{O}} = \frac{\mathcal{O}_1 + \mathcal{O}_2}{2} \quad \Delta\mathcal{O} = \frac{|\mathcal{O}_1 - \mathcal{O}_2|}{\sqrt{2}}$$

- The average prediction $\hat{\mathcal{O}}$ may have no physical meaning (Phillip Litchfield two lane traffic example)



- If \mathcal{O}_1 and \mathcal{O}_2 are both biased in the same way $\rightarrow \Delta\mathcal{O}$ **underestimated**
- If \mathcal{O}_1 accurate and \mathcal{O}_2 is poor $\rightarrow \Delta\mathcal{O}$ **overestimated**

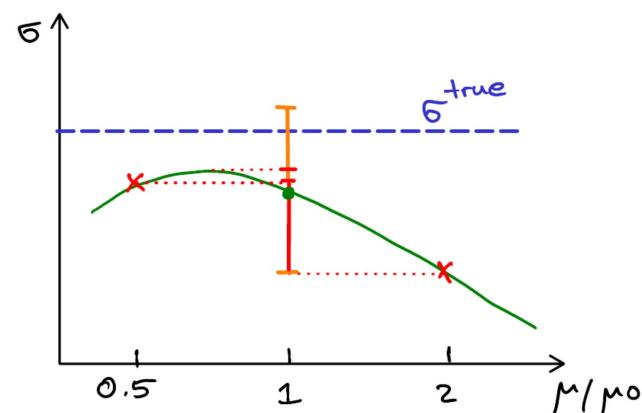
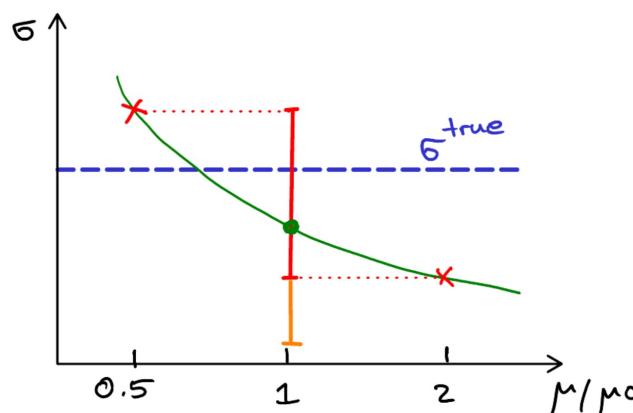
Ugly systematics: parameter variation



- Some systematics uncertainties have a parametric description
- We model an observable as $\mathcal{O}(\theta)$:

$$\mathcal{O}_{true} = \mathcal{O}(\theta_0) \pm \Delta\mathcal{O}$$

- We vary θ to estimate $\Delta\mathcal{O}$
- Ex: Renormalization scale variation



*Frank Tackmann example

Gamma Distributions

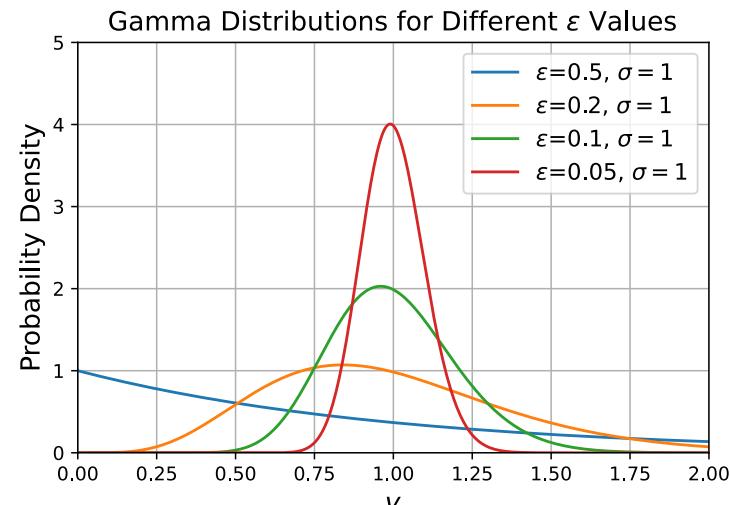


- Treat the systematic variances $\sigma_{u_i}^2$ are *adjustable parameters (nuisance parameter)*.
- Suppose their best estimates v_i are gamma distributed:

$$v \sim \frac{\beta^\alpha}{\Gamma(\alpha)} v^{\alpha-1} e^{-\beta v}$$

$$\alpha = \frac{1}{4\epsilon_i^2} \quad \beta = \frac{1}{4\epsilon_i^2 \sigma_{u_i}^2}$$

- σ_{u_i} Systematic Error
- $\epsilon_i = \frac{1}{2} \frac{\sigma_{v_i}}{\sigma_{u_i}^2} \cong \frac{\sqrt{v_i}}{\sigma_{u_i}}$ relative error on σ_{u_i} : “**Error on error**”



Gamma Variance Model (GVM)



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- The likelihood is modified as follows:

$$L(\boldsymbol{\mu}, \boldsymbol{\theta}, \sigma_{u_i}^2) = P(\mathbf{y}|\boldsymbol{\mu}, \boldsymbol{\theta}) \times \prod_i \frac{1}{\sqrt{2\pi}\sigma_{u_i}} e^{-(u_i - \theta_i)^2/2\sigma_{u_i}^2} \times \frac{\beta_i^{\alpha_i}}{\Gamma(\alpha_i)} v_i^{\alpha_i-1} e^{-\beta_i v_i}$$

- One can profile over $\sigma_{u_i}^2$ in closed form:

$$\log L_P(\boldsymbol{\mu}, \boldsymbol{\theta}) = \log P(\mathbf{y}|\boldsymbol{\mu}, \boldsymbol{\theta}) - \frac{1}{2} \sum_i \left(\mathbf{1} + \frac{1}{2\varepsilon_i^2} \right) \log \left(\mathbf{1} + 2\varepsilon_i^2 \frac{(u_i - \theta_i)^2}{v_i} \right)$$

- We call this model the Gamma Variance Model (GVM)

(see: G. Cowan, Eur. Phys. J. C (2019) 79:133; arXiv:1809.05778)



- Gamma distributions allow to parametrize distributions of positive defined variables (like estimates of variances)
- Using Gamma distributions it is possible to profile in close form over σ_i^2

- Gamma distributions include the case where the variance is estimate from a real dataset of control measurements:

$$v_i = \frac{1}{n_i - 1} \sum (u_{i,j} - \bar{u}_i)^2$$

- $(n - 1)v_i/\sigma_{u_i}^2$ follows a χ_{n-1}^2 distribution and v_i a Gamma distribution with:

$$\alpha_i = \frac{n_i - 1}{2}$$

$$\beta_i = \frac{n_i - 1}{2\sigma_{u_i}^2}$$



- BLUE (Best Linear Unbiased Estimators) approach to combinations:

$$\chi^2 = \sum_i (y_i - f(\mathbf{a})) V_{ij}^{-1} (y_j - f(\mathbf{a}))$$

$$V_{ij} = V_{ij}^{(stat)} + V_{ij}^{(syst)}$$

- $V_{ij}^{(stat)}$: Statistical covariance matrix.
- $V_{ij}^{(syst)}$: Covariance matrix induced by systematic source.
- $V_{ij}^{(syst)} = \sum_s V_{ij}^{(s)}$



- Nuisance parameters approach:

$$\chi^2 = \sum_i \frac{(y_i - f(\mathbf{a}) - \sum_s \Gamma_i^s \theta_s)^2}{\sigma_i^2} + \sum_s \theta_s^2$$

Magnitude of the bias induced by the systematic source s





- Nuisance parameters approach:

$$\chi^2 = \sum_i \frac{(y_i - f(\boldsymbol{a}) - \sum_s \Gamma_i^s \theta_s)^2}{\sigma_i^2} + \sum_s \theta_s^2$$

Magnitude of the bias induced by the systematic source s



- Connection:

$$V_{ij}^{(syst)} = \sum_s V_{ij}^{(s)}$$

$$V_{ij}^{(s)} = \Gamma_i^s \Gamma_j^s$$

- Gamma Variance Model:

$$\chi^2 = \sum_i \frac{(y_i - f(\alpha) - \sum_s \Gamma_i^s \theta_s)^2}{\sigma_i^2} + \sum_s \left(1 + \frac{1}{2\epsilon_i^2} \right) \log(1 + 2\epsilon_i^2 \theta_i^2)$$

- What to do if we do not have access to the factors Γ_i^s (we only know $V_{ij}^{(syst)}$)?

✓ $V_{ij}^{(syst)} = \sum_s V_{ij}^{(s)}$ ✗

- Switch to a nuisance parameters approach:

Proof is non-trivial!

$$\chi^2 = \sum_i \frac{(y_i - \mu - \theta_i)^2}{\sigma_i^2} + \sum_{ij} \theta_i C_{ij}^{-1} \theta_j$$

$$C_{ij} = V_{ij}^{(s)}$$

- Substitute quadratic term with log-constraint:

$$\sum_{ij} \theta_i C_{ij}^{-1} \theta_j \longrightarrow \sum_i \left(N + \frac{1}{2\epsilon_i^2} \right) \log(1 + 2\epsilon_i^2 \theta_i C_{ij}^{-1} \theta_j)$$

- The Hessian method is based on the assumption that the χ^2 follows a χ^2 distribution.
- Our “goodness-of-fit” statistics q is not a χ^2 so will not follow exactly a χ^2 for large values of ϵ^2

Large literature on the topic:

- *Bartlett, M. S. (1937) Proceedings of the Royal Society A, 160, 268–282*
- *Applied Asymptotics Case Studies in Small-Sample Statistics* by A. R. Brazzale, A. C. Davison and N. Reid)
- Canonero, E., Brazzale, A.R. & Cowan, *Eur. Phys. J. C* **83**, 1100 (2023).

- Modify the test statistic q so that its distribution is closer to a χ^2 :

$$q \xrightarrow{\hspace{2cm}} q^* = q \frac{N_{dof}}{E[q]}$$

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Expectation value in the asymptotic limit (degrees of freedom of χ^2)

Exact expectation value

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$$q \xrightarrow{\hspace{2cm}} q^* = q \frac{N_{dof}}{E[q]}$$

Expectation value in the asymptotic limit (degrees of freedom of χ^2)

Exact expectation value

$$q \sim \chi^2 + \mathcal{O}(\epsilon^2)$$

$$q^* \sim \chi^2 + \mathcal{O}(\epsilon^4)$$